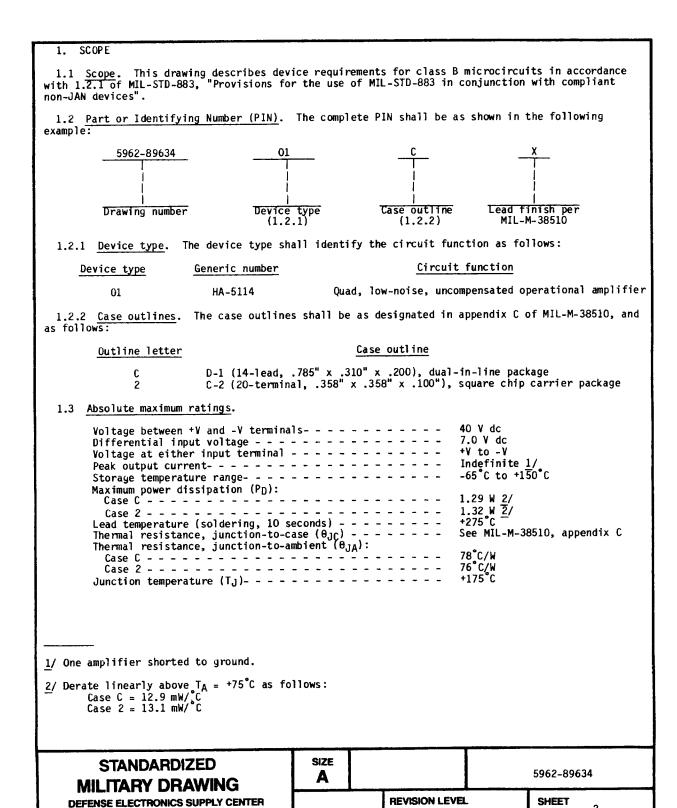
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OF SHEETS PMIC N/A STANDARI MILITA DRAWII	ARY Charles E. Besorl					DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 MICROCIRCUIT, LINEAR, OPERATIONAL AMPLIFIED QUAD, LOW POWER, UNCOMPENSATED, MONOLITHIC SILICON							IER,											
THIS DRAWING IS FOR USE BY ALL D AND AGENCIE DEPARTMENT O AMSC N/A	EPART S OF T	MEN'	TS		AWING 15 N	OVE	1BER					SIZE CAGE CODE 67268 5962 -				-69	63	4						

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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.



U.S. GOVERNMENT PRINTING OFFICE: 1990-750-527R

2

DAYTON, OHIO 45444

1.4 Recommended operating conditions.

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

- Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103

- List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- $3.1~\underline{\text{Item requirements}}$. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.
- 3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-89634
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEV	SHEET 3

DESC FORM 193A SEP 87

★ U.S. GOVERNMENT PRINTING OFFICE 1990-750-527R

TAB	LE I. <u>E</u>	lecti	rical perf	ormanc	e characterist	ics.				
Test	 Symbol 		Cor -55°C < unless of	ditio T _A < herwi	ns +125°C 1/ se specified	Group A subgroups	L Min	imits Max	Unit	
Input offset voltage	\v_{10}	VCM	= 0.0 V			1 1		±2.5	mV	
		1				2,3		 ±3.0	_ 	
Input bias current	+IB	V _{CM} -R _S	= 0.0 V, = 100Ω	+R _S =	10 kΩ,	1	 	±200 	lnA	
	 	 				2,3		±325		
	-IB	I IV _{CM} I-R _S	= 0.0 V, = 10 kΩ	+R _S =	100Ω,	1		 ±200 	nA	
	 					2,3		+325 		
Input offset current	1110	V _{CM} -R ₅	= 0.0 V, = 10 kΩ	+R _S =	10 kΩ,	1		 ±75	nA	
	1) 				2,3		 ±125	- 	
Common mode voltage range	+V _{CM}	+V	= 3.0 V, -	V = ~2	27 V	1,2,3	12		V	
	I-V _{CM}	+V :	= 27 V, -V	= -3	0 V	1,2,3	-12		V	
Large signal voltage gain			T = 0.0 V = 2.0 kΩ	and 10) V,	4,5,6	100		 k V / V 	
	-A _{VOL}	V _{OU} -	$N_{\rm OUT}$ = 0.0 Y and -10 Y, $N_{\rm L}$ = 2.0 k Ω			4,5,6	100		- j 	
Common mode rejection ratio	+CMRR	^V	w = 5.0 V, = -20 V, V	+V = OUT =	10 V, -5.0 V	1,2,3	 86 	 	dB	
	-CMRR	-A \ \ \ \ \ \ \ \ \ \ \ \ \	M = -5.0 V = -10 V, V	, +V =	20 V, 5.0 V	1,2,3	86 		dB 	
See footnotes at end of tabl	e.									
STANDARDIZED			SIZE A		5962-89634					
DEFENSE ELECTRONICS SUPPL	MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444				REVISION LEVEL	<u> </u>				

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TABLE I.	Electric	cal p	erformanc	e char	acteristics -	Continued.			
Test	 Symbol 		Con -55°C <u><</u> unless ot	dition T _{A <} herwis	s +125°C <u>1</u> / e specified	Group A subgroups 		imits Max	Unii
Output current	+I _{OUT}	V _{OUT}	Γ = -5.0 V			1,2,3	10		mA
	-I _{OUT}	v _{ou1}	r = 5.0 V			1,2,3	 -10 	i 	l mA
Output voltage swing	+¥ _{0UT1}	 R _L =	= 2.0 kΩ			1,2,3	10		IV
	l l+V _{OUT2} l	 R _L = 	= 10 kΩ				12	 	
i	 -V _{OUT1}	 R _L =	: 2.0 kΩ			1,2,3	 -10 	 	IV
	-V _{OUT2}	 R _L = 	: 10 kΩ			1	-12		
(wiescent power supply	 +I _{CC}	 Y _{OUT} 	V _{OUT} = 0 V, I _{OUT} = 0 mA					6.5	 mA
	 	 				2,3		7.5	!
	I-I _{CC}	ן דע _ס ען ו	= 0 V, I	OUT =	O mA	1	 	 -6.5	l mA
	! 	 				2,3] 	-7.5	- -
Power supply rejection ratio	 +PSRR 	+V =	: 10 V and	20 V,	-V = -15 V,	1,2,3	 86 		l dB
	-PSRR	-V =	= -10 V an	d -20	V, +V = +15 V	1,2,3	 86 		l I dB I
Differential input resistance <u>2</u> /	I IR _{IN} I	I V _{CM}	= 0.0 V,	T _A = 4	25°C	4	 250 	 	kΩ
Input noise voltage <u>2</u> /	lE _n	$ R_{S} = 20\Omega$, $f_{O} = 1.0 \text{ kHz}$, $ R_{L} = 2.0 \text{ k}\Omega$, $ T_{A} = +25 ^{\circ}\text{C}$			4	 - -	6.0	<u> 3</u> /	
Input noise current <u>2</u> /	I _n	$ R_S = 2.0 \text{ M}\Omega$, $f_0 = 1.0 \text{ kHz}$, $ R_L = 2.0 \text{ k}\Omega$, $ T_A = +25 \text{ C}$				4	 	3.0	4/
See footnotes at end of table	: <u></u>	•	***************************************			· · · · · · · · · · · · · · · · · · ·	•		<u> </u>
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★ U.S. GOVERNMENT PRINTING OFFICE: 1990-750-527R

Tanh	T Symbol	Co	ditions		Group A	Limits		 Unit
Test	Symbol 	-55°C	nditions < T _{A <} +1 Therwise	25°C <u>1</u> / specified	subgroups		Max	- 0111
Slew rate <u>2</u> /	 +SR	 V _{OUT} = -5.0 '	to +5.0	٧,	1 4	12		 Υ/μ
	1	$R_L = 2.0 \text{ k}\Omega$	$T_A = +25$	-c	5,6	10		
	I-SR	 Y _{OUT} = +5.0 \	to -5.0	٧,	i 4	12	† <u>!</u>	 V/μ
	 	$ R_L = 2.0 \text{ k}\Omega$	5, 6	10	1			
Gain bandwidth product <u>2</u> /	GBWP	$V_{OUT} = 200 \text{ mV},$ f = 10 kHz RL = 2.0 k Ω TA = +25°C f = 1.0 MHz		 f = 10 kHz 	4	40	i i	MHz
				 4 	60		_ 	
Full power bandwidth <u>2</u> / <u>5</u> /	 FPBW 	V _{PK} = 10 V, T _A = +25 °C	4	191		k Hz		
Closed loop stable gain <u>2</u> /	 CLSG 	$R_L = 2.0 \text{ k}\Omega$	4,5,6	10	 	 V/V		
Rise time <u>2</u> / <u>6</u> /	t _r	V _{OUT} = 0.0 V T _A = +25 C	9	 -	100	lns I		
Fall time <u>2</u> / <u>6</u> /	tf	V _{OUT} = 0.0 V T _A = +25 C	9	 	100	lns		
Overshoot 2/	 +0S 	V _{OUT} = 0.0 V T _A = +25°C	to +200	m∨,	9		40	1%
	-0S	V _{OUT} = 0.0 V T _A = +25°C	to -200	mV,	9		40	1%
Output resistance <u>2</u> /	ROUT	Open loop, T	t = +25°C		4		150	Ω
Quiescent power consumption 7/	I _{PC}	V _{OUT} = 0 V,	1 _{0UT} = 0	mA	1,2,3		225	mW
See footnotes at end of tabl		SiZE	1	-				
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* U.S. GOVERNMENT PRINTING OFFICE 1990-750-527B

TABLE I. Electrical performance characteristics - Continued.										
Test	 Symbol	Conditions	Group A	Li	 Unit					
		Conditions -55°C < T _A < +125°C 1/ unless otherwise specified	subgroups 	Min	 Max 					
Channel separat	ion CS	$ R_S = 1.0 \text{ k}\Omega$, AyCL = 100 V/V, $ V_{IN} = 100 \text{ mV}$ rms at 10 kHz referred_to input	4	90	 	l dB				
		TA = +25°C	1		<u> </u>	<u> </u>				

- $\frac{1}{2}$ +V = +15 V, -V = -15 V, RS = $100\Omega,$ R_L = 500 $k\Omega,$ C_L = 50 pF, V_{OUT} = 0.0 V, and A_V = 10 V/V unless otherwise specified. Tests apply to each amplifier.
- 2/ If not tested, shall be guaranteed to the limits specified in table I.
- 3/ nV per the square root of frequency expressed in Hz.
- 4/ pA per the square root of frequency expressed in Hz.
- 5/ Full power bandwidth = $\frac{SR}{2 \pi V_{PK}}$.
- 6/ Rise and fall times measured between 10 percent and 90 percent point.
- 7/ (unlessent power consumption based on quiescent supply current test maximum (no load on outputs).

STANDARDIZED MILITARY DRAWING	SIZE A					
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444			REVISION LEVEL		SHEET 7	

★ U.S. GOVERNMENT PRINTING OFFICE: 1990-750-527R

Device types	01	01		
Case outlines	С	2 		
Terminal number	Termina	symbol		
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20	OUT 1 -IN 1 +IN 1 +V +IN 2 -IN 2 OUT 2 OUT 3 -IN 3 +IN 3 +IN 3 -V +IN 4 -IN 4 OUT 4	No connection OUT 1 -IN 1 +IN 1 No connection +V No connection +IN 2 -IN 2 OUT 2 No connection OUT 3 -IN 3 +IN 3 +IN 3 No connection -V No connection -V No connection +IN 4 OUT 4		

FIGURE 1. Terminal connections.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A
5962-89634

REVISION LEVEL
SHEET
8

DESC FORM 193A SEP 87

★ U.S. GOVERNMENT PRINTING OFFICE 1990-750-527R

- 3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103 (see 6.6 herein).
- 3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. OUALITY ASSURANCE PROVISIONS
- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125$ °C, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 7, 8, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

STANDARDIZED MILITARY DRAWING	SIZE A			5962-89634	4
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	-	SHEET	9

* U.S. GOVERNMENT PRINTING OFFICE: 1990-750-527R

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883:
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125$ °C, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*,2,3,4,5,6
 Group A test requirements (method 5005)	1,2,3,4,5,6,9**
Groups C and D end-point electrical parameters (method 5005)	1

- * PDA applies to subgroup 1.
- ** Subgroup 9, if not tested, shall be guaranteed to the limits specified in table I.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

STANDARDIZED MILITARY DRAWING	SIZE A	5962-89634				
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	•	SHEET 10		

DESC FORM 193A SEP 87

★ U.S. GOVERNMENT PRINTING OFFICE: 1990-750-527B

- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.
- 6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5375.
- 6.6 Approved sources of supply. Approved sources of supply are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS.

STANDARDIZED	
MILITARY DRAWING	

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

DESC FORM 193A SEP 87

★ U.S. GOVERNMENT PRINTING OFFICE: 1990-750-527R

STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 1990 NOV 15

Approved sources of supply for SMD $\frac{5962-89634}{1}$ are listed below for immediate acquisition only and shall be added to MIL-BUL-103 during the next revision. MIL-BUL-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-ECS. This bulletin is superseded by the next dated revision of MIL-BUL-103.

Standardized military drawing PIN	Vendor CAGE number	Vendor similar PIN <u>1</u> /
5962-8963401CX	34371	HA1-5114/883
5962-89634012X	34371	HA4-5114/883

1/ Caution. Do not use this number for item

acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE		
number		

Vendor name and address

34371

Harris Semiconductor P.O. Box 883 Melbourne, FL 32901

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.